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_	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/644,048	HYDE ET AL.	
	Examiner	Art Unit	
	Fric B Kiss	2192	

	SEARCHED		
Class	Subclass	Date	Examiner
717	104, 105, 125	9/16/2005	EBK
703	17, 21	9/16/2005	EBK
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INT	ERFERENC	E SEARCH	HED
Class	Subclass	Date	Examiner

SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
PALM Inventor Search	9/16/2005	ЕВК
EAST (USPAT, USPG-PUB, EPO, JPO, DERWENT, IBM_TDB) See Search History printout	9/16/2005	EBK
www.google.com See Search History printout	9/16/2005	ЕВК
717/124 text search only See Search History printout	9/16/2005	EBK
703/22 text search only See Search History printout	9/16/2005	ЕВК
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